

<b>Notice of References Cited</b>	Application/Control No. 10/567,701		Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner JAE Y. LEE		Art Unit 2466	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,915,325	07-2005	Lee et al.	709/202
*	B	US-6,845,100	01-2005	Rinne, Mika	370/395.43
*	C	US-6,466,985	10-2002	Goyal et al.	709/238
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

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